

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination
		09/973,302	CHAIKO, DAVID J.
Examiner	Art Unit	1714	Page 1 of 1
Katarzyna Wyrozebski Lee			

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M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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